



# BT137S-600E

## Sensitive Gate Triacs

HAOPIN MICROELECTRONICS CO.,LTD.

### Description

Passivated, sensitive gate triacs in a plastic envelope, intended for use in general purpose bidirectional switching and phase control applications, where high sensitivity is required in all four quadrants.

| Symbol  | Simplified outline  |
|---|---|
|  | <br>TO-252 |
| Pin   | Description   |
| 1   | Main terminal 1 (T1)  |
| 2   | Main terminal 2 (T2)  |
| 3   | gate (G)  |
| TAB   | Main terminal 2 (T2)  |

### Applications:

- ◆ Motor control
- ◆ Industrial and domestic lighting
- ◆ Heating
- ◆ Static switching

### Features

- ◆ Blocking voltage to 600 V
- ◆ On-state RMS current to 8 A

| SYMBOL      | PARAMETER                            | Value | Unit |
|-------------|--------------------------------------|-------|------|
| $V_{DRM}$   | Repetitive peak off-state voltages   | 600   | V    |
| $I_T$ (RMS) | RMS on-state current                 | 8     | A    |
| $I_{TSM}$   | Non-repetitive peak on-state current | 65    | A    |

| SYMBOL       | PARAMETER                                       | CONDITIONS                                 | MIN | TYP | MAX | UNIT |
|--------------|---|--|-----|-----|-----|------|
| $R_{thj-mb}$ | Thermal resistance<br>Junction to mounting base | Full cycle                                 | -   | -   | 2.0 | K/W  |
|              |   | Half cycle                                 | -   | -   | 2.4 | K/W  |
| $R_{thj-a}$  | Thermal resistance<br>Junction to ambient       | Pcb(FR4)mounted;<br>footprint as in Fig.14 | -   | 75  | -   | K/W  |



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Limiting values in accordance with the Maximum system(IEC 134)

| SYMBOL       | PARAMETER  | CONDITIONS  | MIN      | MAX | UNIT         |
|--------------|--|---|----------|-----|--------------|
| $V_{DRM}$    | Repetitive peak off-state Voltages                           |   | -        | 600 | V            |
| $I_{T(RMS)}$ | RMS on-state current   | Full sine wave; $T_{mb} \leq 102^\circ C$               | -        | 8   | A            |
|              | Non-repetitive peak On-state current                         | full sine wave;<br>$T_j = 25^\circ C$<br>prior to surge | $t=20ms$ | 65  | A            |
| $DI_t/dt$    | Repetitive rate of rise of on-state current after triggering | $I_{TM}=12A$ ; $I_G=0.2A$ ;<br>$DI_G/dt=0.2A/\mu s$     | $T2+G+$  | -   | $50 A/\mu s$ |
|              |  |   | $T2+G-$  | -   | $50 A/\mu s$ |
|              |  |   | $T2-G-$  | -   | $50 A/\mu s$ |
|              |  |   | $T2-G+$  | -   | $10 A/\mu s$ |
|              |  |   |          |     |              |
| $I_{GM}$     | Peak gate current  |   | -        | 2   | A            |
| $V_{GM}$     | Peak gate voltage  |   | -        | 5   | V            |
| $P_{GM}$     | Peak gate power  |   | -        | 5   | W            |
| $P_{G(AV)}$  | Average gate power   | Over any 20 ms period                                   | -        | 0.5 | W            |
| $T_{stg}$    | Storage temperature  |   | -40      | 150 | °C           |
| $T_j$        | Operating junction Temperature                               |   | -        | 125 | °C           |

$T_j=25^\circ C$  unless otherwise stated

| SYMBOL                 | PARAMETER                 | CONDITIONS  | MIN     | TYP  | MAX        | UNIT     |        |
|------------------------|---------------------------|---|---------|------|------------|----------|--------|
| Static characteristics |                           |   |         |      |            |          |        |
| $I_{GT}$               | Gate trigger current      | $V_D=12V$ ; $I_T=0.1A$  | $T2+G+$ | -    | 2.5        | mA       |        |
|                        |                           |   | $T2+G-$ | -    | 4.0        | mA       |        |
|                        |                           |   | $T2-G-$ | -    | 5.0        | mA       |        |
|                        |                           |   | $T2-G+$ | -    | 11         | mA       |        |
| $I_L$                  | Latching current          | $V_D=12V$ ; $I_{GT}=0.1A$   | $T2+G+$ | -    | 3.0        | mA       |        |
|                        |                           |   | $T2+G-$ | -    | 14         | mA       |        |
|                        |                           |   | $T2-G-$ | -    | 3.0        | mA       |        |
|                        |                           |   | $T2-G+$ | -    | 4.0        | mA       |        |
| $I_H$                  | Holding current           | $V_D=12V$ ; $I_{GT}=0.1A$   |         | -    | 2.5        | mA       |        |
| $V_T$                  | On-state voltage          | $I_T=10A$   |         | -    | 1.3        | 1.65     | V      |
| $V_{GT}$               | Gate trigger voltage      | $V_D=12V$ ; $I_T=0.1A$<br>$V_D=400V$ ; $I_T=0.1A$ ; $T_j=125^\circ C$ |         | 0.25 | 0.7<br>0.4 | 1.5<br>- | V<br>V |
| $I_D$                  | Off-state leakage current | $V_D=V_{DRM(max)}$ ; $T_j=125^\circ C$                                |         | -    | 0.1        | 0.5      | mA     |

### Dynamic Characteristics

|             |  |  |   |    |   |           |
|-------------|--|--|---|----|---|-----------|
| $D_{VD}/dt$ | Critical rate of rise of Off-state voltage | $V_{DM}=67\% V_{DRM(max)}$ ; $T_j=125^\circ C$ ;<br>Exponential wave form; Gate open circuit | - | 50 | - | $V/\mu s$ |
| $t_{gt}$    | Gate controlled turn-on time               | $I_{TM}=12A$ ; $V_D=V_{DRM(max)}$ ; $I_G=0.1A$ ;<br>$DI_G/dt=5A/\mu s$                       | - | 2  | - | $\mu s$   |

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### Description

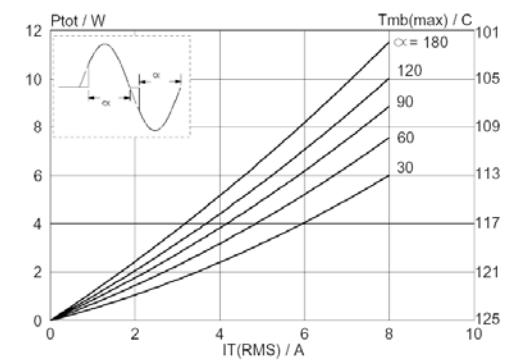


Fig.1. Maximum on-state dissipation,  $P_{tot}$ , versus rms on-state current,  $I_{T(RMS)}$ , where  $\alpha$  = conduction angle.

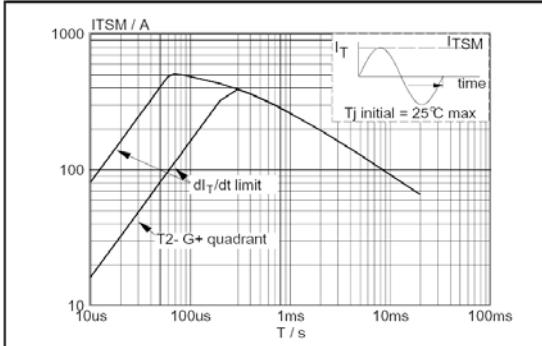


Fig.2. Maximum permissible non-repetitive peak on-state current  $I_{TSM}$ , versus pulse width  $t_p$ , for sinusoidal currents,  $t_p \leq 20\text{ms}$ .

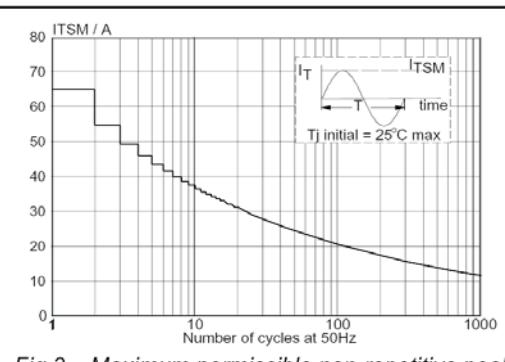


Fig.3. Maximum permissible non-repetitive peak on-state current  $I_{TSM}$ , versus number of cycles, for sinusoidal currents,  $f = 50\text{ Hz}$ .

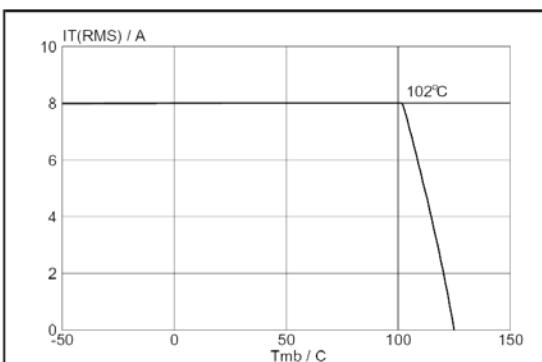


Fig.4. Maximum permissible rms current  $I_{T(RMS)}$ , versus mounting base temperature  $T_{mb}$ .

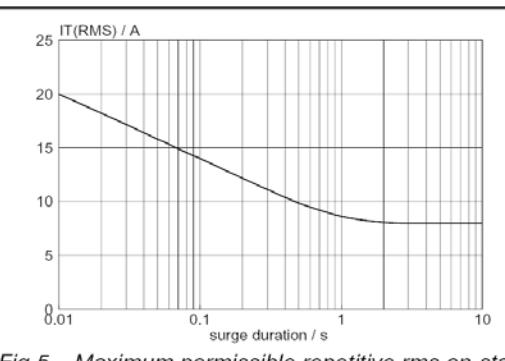


Fig.5. Maximum permissible repetitive rms on-state current  $I_{T(RMS)}$ , versus surge duration, for sinusoidal currents,  $f = 50\text{ Hz}$ ;  $T_{mb} \leq 102^\circ\text{C}$ .

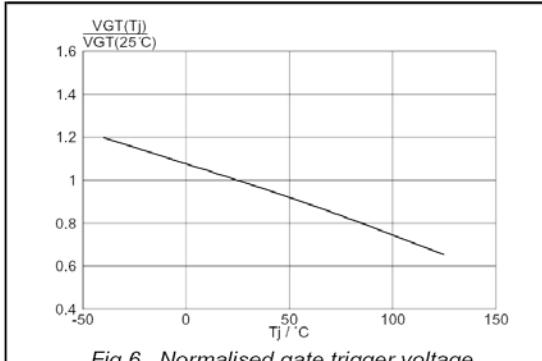


Fig.6. Normalised gate trigger voltage  $V_{GT}(T_j)/V_{GT}(25^\circ\text{C})$ , versus junction temperature  $T_j$ .

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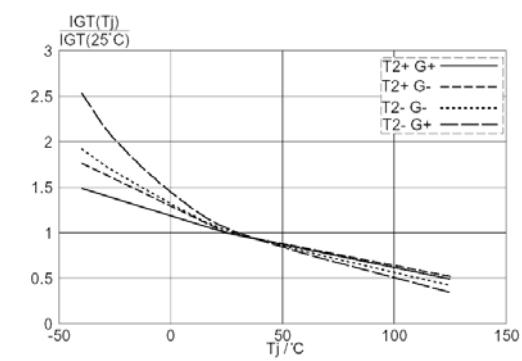


Fig.7. Normalised gate trigger current  $I_{GT}(T_j)/I_{GT}(25^\circ C)$ , versus junction temperature  $T_j$ .

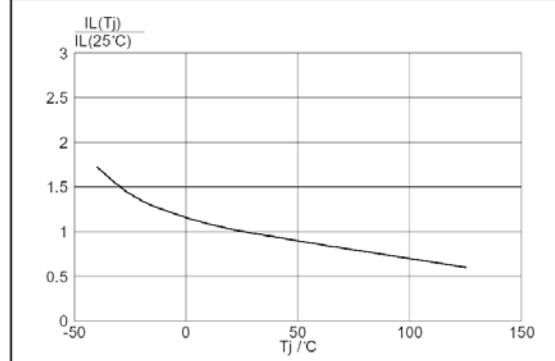


Fig.8. Normalised latching current  $I_L(T_j)/I_L(25^\circ C)$ , versus junction temperature  $T_j$ .

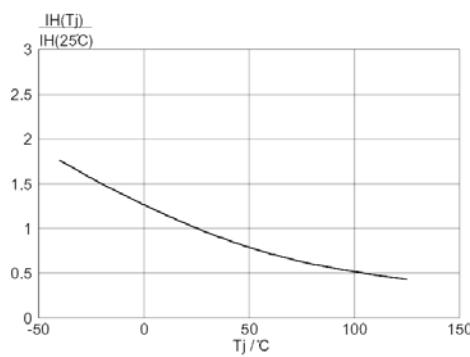


Fig.9. Normalised holding current  $I_H(T_j)/I_H(25^\circ C)$ , versus junction temperature  $T_j$ .

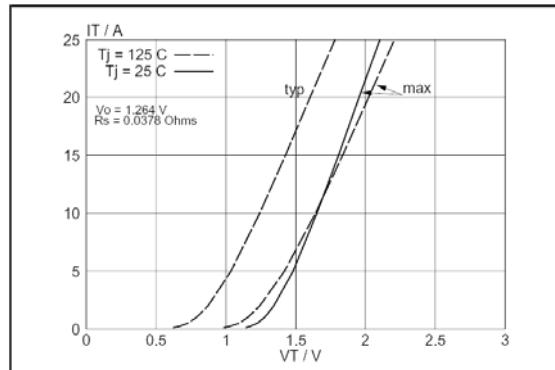


Fig.10. Typical and maximum on-state characteristic.

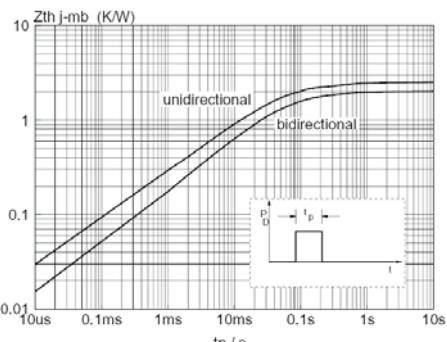


Fig.11. Transient thermal impedance  $Z_{th\ j\ -mb}$ , versus pulse width  $t_p$ .

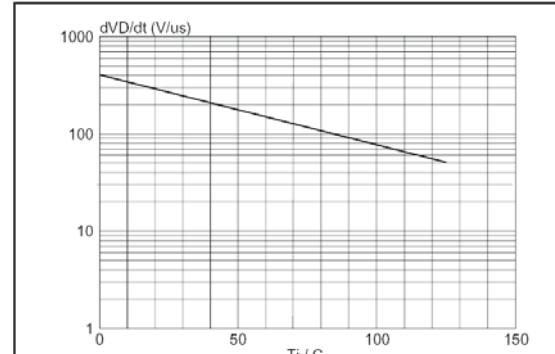


Fig.12. Typical, critical rate of rise of off-state voltage,  $dV_D/dt$  versus junction temperature  $T_j$ .

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## MECHANICAL DATA

